



Journal of Nanomaterials

Special Issue on  
**Testing, Measurement, and Characterization of  
Nanomaterials**

# CALL FOR PAPERS

Characterization of materials at the nanoscale has recently attracted significant attention due to the emergence of various novel nanoscale materials and structures over the past decade. Nanomaterials have shown great potential in a broad range of applications from nanocomposites to nanoelectronics and nanoelectromechanical systems (NEMS). Before the prevailing applications of these nanostructures, it is of particular relevance to well understand their mechanical, electrical, thermal, optical, and biological properties. However, due to the very small size of particles/grains, they have presented new challenges during testing, measurement, and characterization of their properties.

We invite investigators to contribute original research articles as well as review articles that will stimulate the developing of novel techniques to test and characterize nanomaterials. We are particularly interested in articles describing the new techniques to characterize the properties of bioinspired nanomaterials.

Potential topics include, but are not limited to:

- ▶ *In situ* electromechanical testing of nanowires and nanotubes
- ▶ *In vivo* characterization of bionanomaterials
- ▶ Measurement of the thermal properties of nanomaterials
- ▶ Optical characterization of nanomaterials
- ▶ AFM based nanoscale testing
- ▶ Nanomanipulation of structures and objects
- ▶ Nanoindentation
- ▶ TEM and HRTEM
- ▶ Other characterization and testing methods of nanomaterials

Authors can submit their manuscripts via the Manuscript Tracking System at <http://mts.hindawi.com/submit/journals/jnm/tmc/>.

**Lead Guest Editor**

Bei Peng, University of Electronic Science and Technology of China, Chengdu, China  
[beipeng@uestc.edu.cn](mailto:beipeng@uestc.edu.cn)

**Guest Editors**

Changhong Ke, Binghamton University, State University of New York (SUNY), Binghamton, USA  
[cke@binghamton.edu](mailto:cke@binghamton.edu)

Yaling Liu, Lehigh University, Bethlehem, USA  
[yal310@lehigh.edu](mailto:yal310@lehigh.edu)

Yong Zhu, North Carolina State University, Raleigh, USA  
[yong\\_zhu@ncsu.edu](mailto:yong_zhu@ncsu.edu)

**Manuscript Due**

Friday, 30 January 2015

**First Round of Reviews**

Friday, 24 April 2015

**Publication Date**

Friday, 19 June 2015